Source of uncertainty	4μ	$2e2\mu$	$2\mu 2e$	4e	combined
Electron reconstruction and identification efficiencies	_	1.7%	3.3%	4.4%	1.6%
Electron isolation and impact parameter selection	_	0.07%	1.1%	1.2%	0.5%
Electron trigger efficiency	_	0.21%	0.05%	0.21%	< 0.2%
$\ell\ell + ee$ backgrounds	_	_	3.4%	3.4%	1.3%
Muon reconstruction and identification efficiencies	1.9%	1.1%	0.8%	_	1.5%
Muon trigger efficiency	0.6%	0.03%	0.6%	_	0.2%
$\ell\ell + \mu\mu$ backgrounds	1.6%	1.6%	_	_	1.2%
QCD scale uncertainty					6.5%
PDF, α_s uncertainty					6.0%
$H \to ZZ^*$ branching ratio uncertainty					4.0%